

**Answer Sheet for Part A**

**APhO 2002**

Name	Student No.	Country	Page No	Total No of pages

(1) : Determine the plane of polarization of the incident laser light.

(a) *Relative orientation of diode laser and polarizer (difference in degree between the angular settings of the diode laser rotary stage and the polarizer rotary stage)*

*The difference in the two angles (in degree) = \_\_\_\_\_ (0.2 point)*

(b) *Brewster angle of incidence  $\theta_i$  for the glass plate = \_\_\_\_\_ (0.2 point)*

*Submit data on blank sheet*

*Graph of reflected laser power versus angular setting of the polarizer rotary stage*

*(0.4 point)*

*Angular setting of the polarizer rotary stage*

*for axis of polarization parallel to the plane of incidence = \_\_\_\_\_ (0.2 point)*

(2): Measure the reflectance  $R_p$  and  $R_s$  of the semiconductor wafer

(a) *Reflectance  $R_p$  (plane of polarization parallel to the plane of incidence)*

*Parameters of your instrument:*

(i) *Angular setting of the polarizer rotary stage = \_\_\_\_\_*

(ii) *Angular setting of the diode laser rotary stage = \_\_\_\_\_*

(iii) *Measured incidence laser power  $I_i$  = \_\_\_\_\_ (mW) (no point)*

*Measurement, calculation of  $R_p$*

*and graph of  $R_p$  versus incident angle (3 points)*

(b) *Reflectance  $R_s$  (plane of polarization perpendicular to the plane of incidence)*

*Parameters of your instrument:*

(i) *Angular setting of the polarizer rotary stage = \_\_\_\_\_*

(ii) *Angular setting of the diode laser rotary stage = \_\_\_\_\_*

(iii) *Measured incidence laser power  $I_i$  = \_\_\_\_\_ (mW) (no point)*

Measurement, calculation of  $R_s$   
and graph of  $R_s$  versus incident angle

(2 points)

(3): Calculate the refractive index of the semiconductor sample

(a) Derivation of equation relating the refractive index  $n$  to  $\pm\sqrt{R_p}$  and  $\sqrt{R_s}$

(Submit derivation on blank sheet)

(0.5 point)

The sign (s) of  $\pm\sqrt{R_p}$  : \_\_\_\_\_  
\_\_\_\_\_

(0.5 point)

(b) Six values of  $n$

angle of incidence $\theta_i$	$R_p$	$R_s$	$n$
20			
30			
40			
50			
60			
80			

(2 points)

Mean and standard deviation  $\sigma_n$  for  $n$

$n$ (mean) = $\sigma_n$ =
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(0.4 point)

(c) Reflectance  $R_s$  and  $R_p$  of the semiconductor at normal incidence.

$R_s$ =            % $R_p$ =            %
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Refractive index  $n$  = \_\_\_\_\_

(0.6 point)